A5G26S008N

Airfast RF Power GaN Transistor

Rev. 4 — 18 October 2023

Product data sheet



1 General description

This 27 dBm RF power GaN transistor is designed for cellular base station applications covering the frequency range of 2300 to 2690 MHz.

2 Features and benefits

- · High terminal impedances for optimal broadband performance
- Designed for low complexity linearization systems
- · Universal broadband driver
- · Optimized for massive MIMO active antenna systems for 5G base stations

3 Typical performance

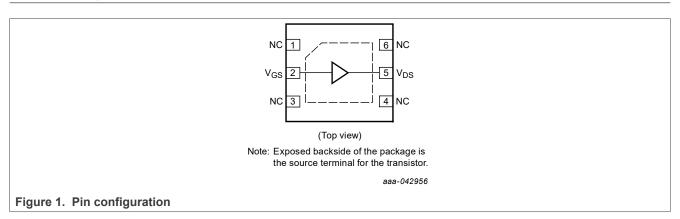
Table 1. 2600 MHz — Typical single-carrier W-CDMA reference circuit performance $V_{DD} = 48 \text{ Vdc}$, $I_{DQ} = 17 \text{ mA}$, $P_{out} = 27 \text{ dBm Avg.}$, $I_{DQ} = 17 \text{ mA}$,

Frequency	G _{ps} (dB)	η _D (%)	Output PAR (dB)	ACPR (dBc)
2496 MHz	19.0	15.8	10.1	-41.0
2595 MHz	19.4	16.5	10.1	-42.4
2690 MHz	18.8	16.4	9.9	-43.6

[1] All data measured with device soldered to NXP reference circuit.



4 Pinning information



5 Ordering information

Table 2. Ordering information

Device	Tape and Reel Information	Package
A5G26S008NT6	T6 Suffix = 5,000 Units, 12 mm Tape Width, 13-inch Reel	DFN 4.5 × 4

6 Product marking

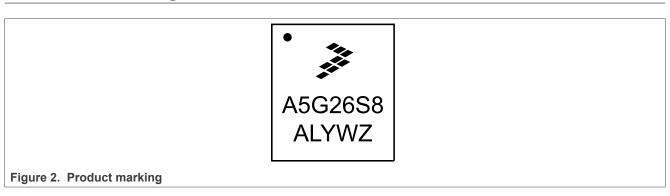


Table 3. Product marking trace code

Identifier	Description
Α	Assembly location
L	Wafer lot indicator
YW	Date code
Z	Assembly lot

7 Limiting values

Table 4. Limiting values

Rating	Symbol	Value	Unit
Drain-Source Voltage	V _{DSS}	125	Vdc
Gate-Source Voltage	V _{GS}	-16, 0	Vdc
Operating Voltage	V_{DD}	55	Vdc
Maximum Forward Gate Current @ T _C = 25°C	I _{GMAX}	1.5	mA
Storage Temperature Range	T _{stg}	-65 to +150	°C
Case Operating Temperature Range	T _C	-55 to +150	°C
Maximum Channel Temperature	T _{CH}	225	°C

8 Recommended operating conditions

Table 5. Recommended operating conditions

Characteristic	Symbol	Value	Unit
Operating Voltage	V_{DD}	48	Vdc

9 Thermal characteristics

Table 6. Thermal characteristics

Characteristic	Symbol	Value	Unit
Thermal Resistance by Infrared Measurement, Active Die Surface-to-Case Case Temperature 118.6°C, P_D = 2.6 W	R _{θJC} (IR)	7.3 ^[1]	°C/W
Thermal Resistance by Finite Element Analysis, Channel-to-Case Case Temperature 118.6°C, P _D = 2.6 W	R _{0CHC} (FEA)	17.8 ^[2]	°C/W

^[1] Refer to AN1955, Thermal Measurement Methodology of RF Power Amplifiers. Go to http://www.nxp.com/RF and search for AN1955.

10 ESD protection characteristics

Table 7. ESD protection characteristics

Test Methodology	Class
Human Body Model (per JS-001-2017)	1A
Charge Device Model (per JS-002-2014)	C3

11 Moisture sensitivity level

Table 8. Moisture sensitivity level

Test Methodology	Rating	Rating Package Peak Temperature	
Per JESD22-A113, IPC/JEDEC J-STD-020	3	260	°C

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Recha (FEA) must be used for purposes related to reliability and limitations on maximum channel temperature. MTTF may be estimated by the expression MTTF (hours) = 10^[A + B/(T + 273)], where *T* is the channel temperature in degrees Celsius, *A* = –11.6 and *B* = 9129.

12 Electrical characteristics

12.1 DC characteristics

12.1.1 DC characteristics — off characteristics

Table 9. DC characteristics — off characteristics

 $(T_A = 25$ °C unless otherwise noted)

Characteristic	Symbol	Min	Тур	Max	Unit
Off characteristics					
Off-State Drain Leakage	I _{D(BR)}	_	_	0.67	mAdc
$(V_{DS} = 150 \text{ Vdc}, V_{GS} = -8 \text{ Vdc})$, ,				

12.1.2 DC characteristics — on characteristics

Table 10. DC characteristics — on characteristics

 $(T_A = 25^{\circ}C \text{ unless otherwise noted})$

Characteristic	Symbol	Min	Тур	Max	Unit
On characteristics					
Gate Threshold Voltage $(V_{DS} = 10 \text{ Vdc}, I_D = 1.52 \text{ mAdc})$	V _{GS(th)}	-3.3	-2.3	-2.0	Vdc
Gate Quiescent Voltage $(V_{DD} = 48 \text{ Vdc}, I_{D} = 17 \text{ mAdc}, Measured in Functional Test})$	$V_{GS(Q)}$	-2.78	-2.5	-2.30	Vdc
Gate-Source Leakage Current (V _{DS} = 150 Vdc, V _{GS} = –12 Vdc)	I _{GSS}	-0.67	_	_	mAdc

12.2 Functional tests

Table 11. Functional tests

(In NXP Production ATE^[1] Test Fixture, T_A = 25°C unless otherwise noted, 50 ohm system)^[2] V_{DD} = 48 Vdc, I_{DQ} = 17 mA, P_{out} = 27 dBm Avg., f = 2595 MHz, 1-tone CW.

Characteristic	Symbol	Min	Тур	Max	Unit
Power Gain	G _{ps}	16.0	18.4	20.0	dB
Drain Efficiency	η_{D}	14.5	16.0	_	%
Saturated Power (Pulsed CW, 5% Duty Cycle)	P _{sat}	39.5	40.5	_	dBm

^[1] ATE is a socketed test environment.

^[2] Internally matched part.

12.3 Wideband ruggedness

Table 12. Wideband ruggedness

(In NXP Reference Circuit, T_A = 25°C unless otherwise noted, 50 ohm system)^[1] I_{DQ} = 17 mA, f = 2595 MHz, Additive White Gaussian Noise (AWGN) with 10 dB PAR.

Characteristic	Symbol	Min	Тур	Max	Unit
ISBW of 400 MHz at 55 Vdc, 0.5 W Avg. Modulated Output Power	No Device Degradation				
(3 dB Input Overdrive from 0.5 W Avg. Modulated Output Power)					

^[1] All data measured with device soldered to NXP reference circuit.

12.4 Typical performance

Table 13. Typical performance

(In NXP Reference Circuit, T_A = 25°C unless otherwise noted, 50 ohm system)^[1] V_{DD} = 48 Vdc, I_{DQ} = 17 mA, 2496–2690 MHz Bandwidth.

Characteristic	Symbol	Min	Тур	Max	Unit
Fast CW, 27 ms sweep					
Saturated Power	P _{sat}	_	10.7	_	W
AM/PM (Maximum value measured at saturated power across the 2496–2690 MHz bandwidth)	Φ	_	-8	_	۰
Gain Variation @ Avg. Power over Temperature (-40°C to +85°C)	ΔG	_	0.017	_	dB/°C
Output Power Variation @ Saturated Power over Temperature (-40°C to +85°C)	ΔP_{sat}	_	0.001	_	dB/°C
Single-carrier W-CDMA, unclipped					
Gain Flatness in 194 MHz Bandwidth @ P _{out} = 27 dBm Avg.	G _F	_	0.7	_	dB
2-tone CW					
VBW Resonance Point (IMD Third Order Intermodulation Inflection Point)	VBW _{res}	_	300	_	MHz

^[1] All data measured with device soldered to NXP reference circuit.

Correct biasing sequence for GaN depletion mode transistors

Turning the device ON

- 1. Set V_{GS} to the pinch-off voltage, typically –5 V.
- 2. Turn on V_{DS} to nominal supply voltage (+48 V).
- 3. Increase V_{GS} until I_{DS} current is attained.
- 4. Apply RF input power to desired level.

Turning the device OFF

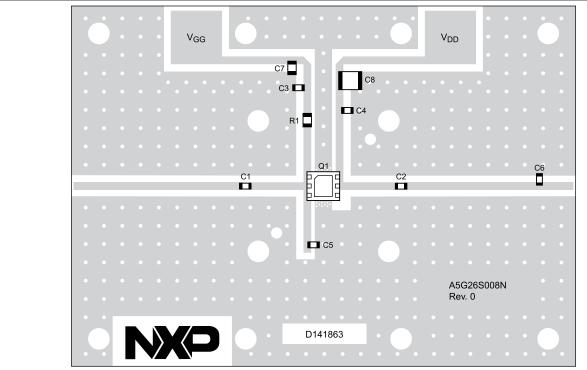
- 1. Turn RF power off.
- 2. Reduce V_{GS} down to the pinch-off voltage, typically $-5\ V$.
- 3. Adjust drain voltage V_{DS} to 0 V. Allow adequate time for drain voltage to reduce to 0 V from external drain capacitors.
- 4. Turn off V_{GS}.

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13 Component layout and parts list

13.1 Component layout



Note: All data measured with device soldered to NXP reference circuit.

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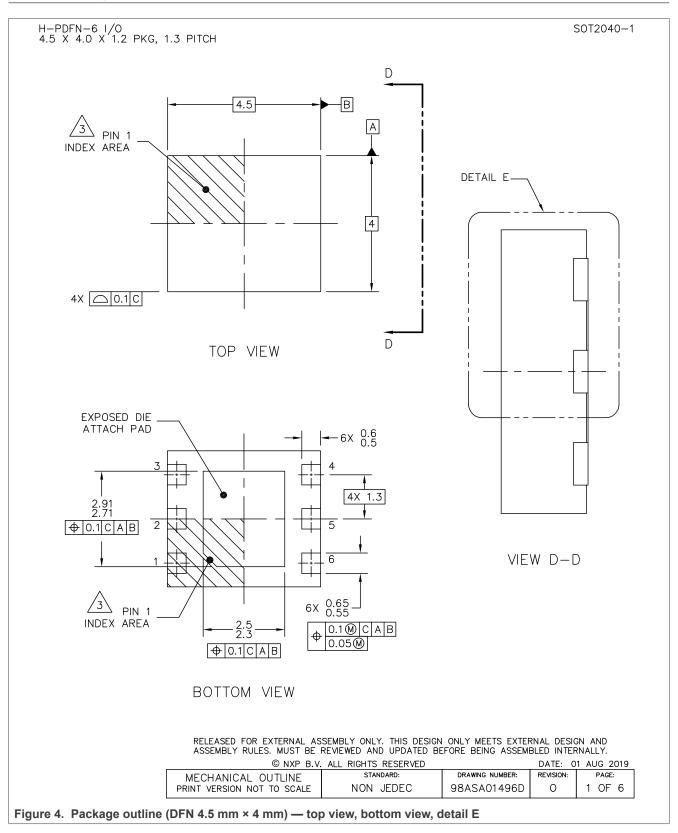
Figure 3. A5G26S008N reference circuit component layout

13.2 Component designations and values

Table 14. A5G26S008N reference circuit component designations and values

Part	Description	Part Number	Manufacturer
C1, C2, C3, C4	5.6 pF Chip Capacitor	600S5R6CT250XT	ATC
C5	0.4 pF Chip Capacitor	600S0R4BT250XT	ATC
C6	0.3 pF Chip Capacitor	600S0R3BT250XT	ATC
C7	1 μF Chip Capacitor	08055C105KAT2A	AVX
C8	4.7 μF Chip Capacitor	C3225X7S2A475M	TDK
Q1	RF Power GaN Transistor	A5G26S008N	NXP
R1	3.3 Ω, 1/8 W Chip Resistor	CRCW08053R30FKEA	Vishay
РСВ	Roger RO4350B, 0.020", ε_{r} = 3.66	D141863	MTL

14 Package information



H-PDFN-6 I/O 4.5 X 4.0 X 1.2 PKG, 1.3 PITCH SOT2040-1 1.25 1.15 -(0.203) 0.08 C 0.05 -(0.6) - (1.3) -SEATING PLANE DETAIL E VIEW ROTATED 90°CW RELEASED FOR EXTERNAL ASSEMBLY ONLY. THIS DESIGN ONLY MEETS EXTERNAL DESIGN AND ASSEMBLY RULES. MUST BE REVIEWED AND UPDATED BEFORE BEING ASSEMBLED INTERNALLY. © NXP B.V. ALL RIGHTS RESERVED DATE: 01 AUG 2019 MECHANICAL OUTLINE PRINT VERSION NOT TO SCALE DRAWING NUMBER: STANDARD: REVISION: PAGE:

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Figure 5. Package outline (DFN 4.5 mm × 4 mm) — detail E, rotated

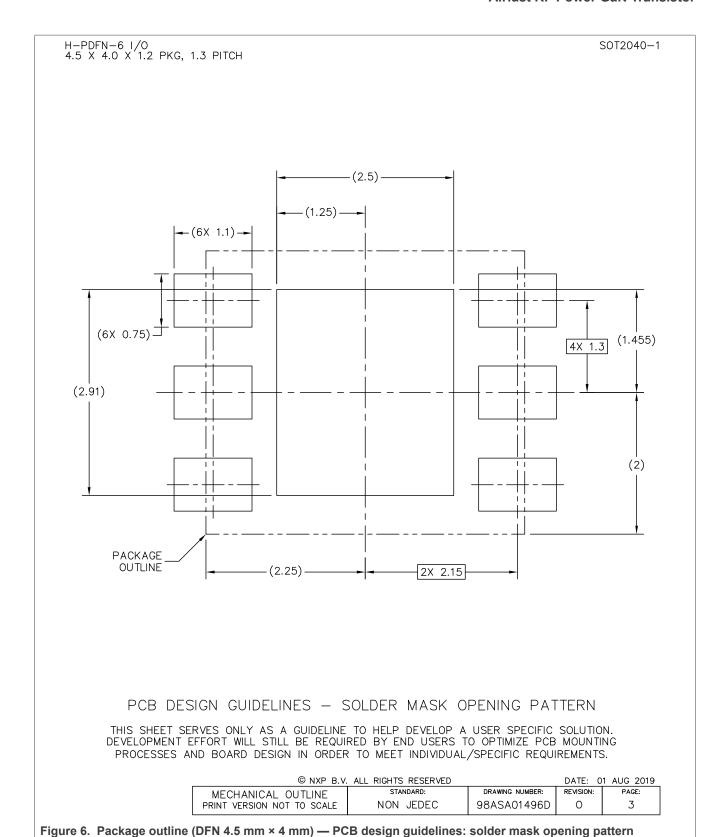
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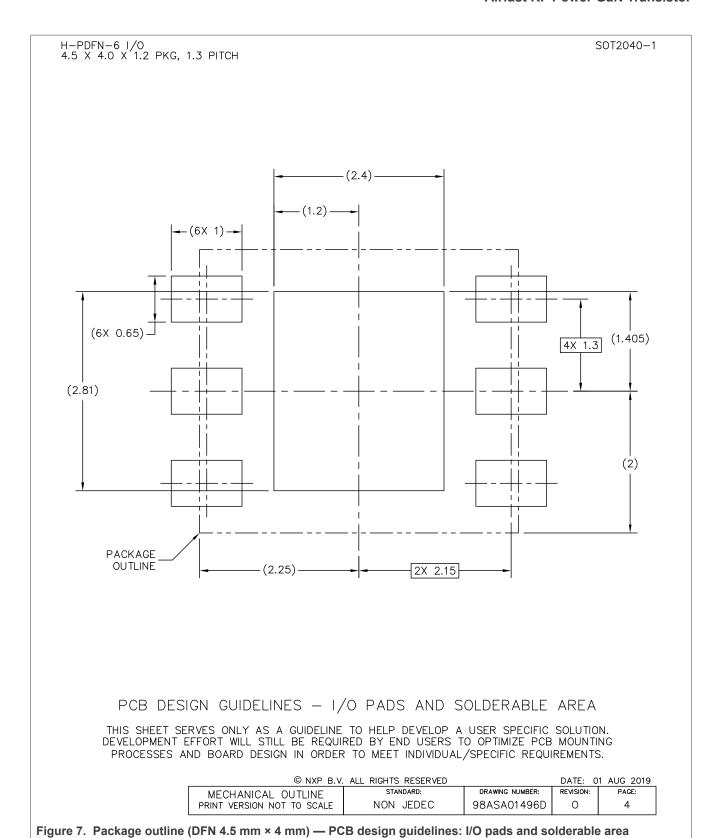
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2



A5G26S008N



H-PDFN-6 I/O 4.5 X 4.0 X 1.2 PKG, 1.3 PITCH SOT2040-1 (4X 0.95) |-2X 0.575 ←(6X 1) - (6X 0.65) 4X 1.3 2X 0.65 (4X 1.1) (2) PACKAGE OUTLINE - (2.25) **—** 2X 2.15 RECOMMENDED STENCIL THICKNESS 0.125 OR 0.15

PCB DESIGN GUIDELINES - SOLDER PASTE STENCIL

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Figure 8. Package outline (DFN 4.5 mm × 4 mm) — PCB design guidelines: solder paste stencil

H-PDFN-6 I/O 4.5 X 4.0 X 1.2 PKG, 1.3 PITCH SOT2040-1

NOTES:

- 1. ALL DIMENSIONS ARE IN MILLIMETERS.
- 2. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.

3.

 $\sqrt{3}$. PIN 1 FEATURE SHAPE, SIZE AND LOCATION MAY VARY.

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Figure 9. Package outline (DFN 4.5 mm × 4 mm) — notes

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15 Product documentation, software and tools

Refer to the following resources to aid your design process.

Application notes

- AN1907: Solder Reflow Attach Method for High Power RF Devices in Plastic Packages
- AN1955: Thermal Measurement Methodology of RF Power Amplifiers

Software

• .s2p File

Development tools

· Printed Circuit Boards

16 Revision history

The following table summarizes revisions to this document.

Table 15. Revision history

Revision	Date	Description
0	26 October 2021	Initial release of data sheet
1	30 November 2022	 Table 1, Maximum Ratings: Gate-Source Voltage: updated -8, 0 to -16, 0 Vdc, p. 2 Table 4, ESD Protection Characteristics, Human Body Model: updated to reflect test data, p. 2 General updates made to align data sheet to current standard
2	7 February 2023	Table 6, DC On Characteristics, V _{GS(Q)} : Min and Max values updated to match production test values, p. 2
3	12 April 2023	 Updated frequency band of operation for this device to 2300–2690 MHz, p. 1 Table 9, Product Marking Trace Code: added, p. 5 General updates made to align data sheet to current standard
4	18 October 2023	 Table 11, Functional Tests: updated output power test condition, p. 4 General updates made to align data sheet to current standard

17 Legal information

17.1 Data sheet status

Document status ^{[1][2]}	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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- [2] The term 'short data sheet' is explained in section "Definitions".
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Airfast RF Power GaN Transistor

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